

Detecting Level 3 Features in Fingerprints Using Support Vector Machines

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Objectives

- Discuss the characteristics of fingerprint features.
- Propose a subset of Level 3 features.
- Describe the methods used to identify level 3 features using Support Vector Machines.
- Review characteristics of Support Vector Machines.
- Discuss typical features in the training and test sets.
- Present performance results.

A Preliminary Report

- This is a project in progress.
- Current results are based on a small data set with only a pore feature set collected from 500 dpi live-scanned images.
- Ultimate goal is to reliably detect several different level 3 features in latent, inked, and live-scanned fingerprints.

Strategy

- Difficult to determine how human fingerprint examiner makes decisions
 - Highly intuitive decisions
 - Expressing decisions as rules is probably impossible
- Instead, emulate examiner's decisions by training a learning machine
 - Capture expertise implicitly in examples
 - Train SVM (Support Vector Machine) to duplicate examiners observed behavior

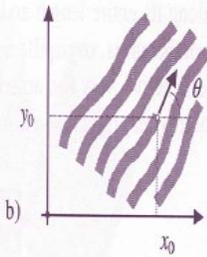
Level 1 Features



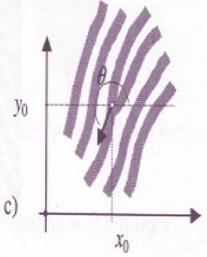
Level 2 Features

	Termination
	Bifurcation
	Lake
	Independent ridge
	Point or island
	Spur
	Crossover

a)



b)



c)

Level 3 Features

- In the broadest sense, level 3 features are any not classifiable as Level 1 and Level 2.
- There is no generally agreed upon definition of Level 3 features.
- A NIST working group is in the process of defining Level 3 features.
 - No conclusions as this is written.

Some Level 3 Feature Candidates

- Pores



- Warts



- Ridge Shapes



- Creases



- Incipient Ridges



- Deformations



- Scars



From: BIOMETRICS
Dr. Andrzej Drygajlo

Sweat Pore Chosen As Feature

- The sweat pore feature was selected for this first portion of the study by two criteria:
 - Usefulness to examiners
 - Detectability by Support Vector Machines
- Disadvantage: Sweat pores may not be visible
 - Ink and powder tends to fill pores
- Advantages
 - Numerous
 - 2700 per square inch (approx.)
 - Distinctive
 - Highly variable in:
 - Size: 88 to 220 microns
 - Spacing along ridge is random (9-18 pores/cm or ridge approx.)
 - In any position across ridge
 - Shape: round, oblong, triangular

Examples of Sweat Pores at 500 dpi



Image Enhancement

- Conservative enhancement used to preserve information
 - Contrast and brightness enhancement by level adjustments
 - Sharpening (un-sharp mask)
- 500 dpi original image
 - Captured with solid-state fingerprint sensor

Image Enhancement Example

Original



Enhanced



Support Vector Machines

- Support Vector Machines (SVM)
 - Learning machines based on statistical learning theory
 - Trained by examples
 - Classifies previously unseen inputs
- Solid mathematical foundation in Vapnik Chervonenkis theory [Vapnik, 1995a][Smola, 2000]
- Maps training vectors into higher (possibly infinite) dimensional space
 - Using “kernel trick” all computation is done with dot products in low dimensional training vector space.
- All the following were once considered to be different classes of Artificial Neural Networks.
 - Radial Basis Function
 - Sigmoidal Multi-layer Perceptron
 - Polynomial
 - Linear
 - Many others
- All the above have been shown to be special cases of an SVM

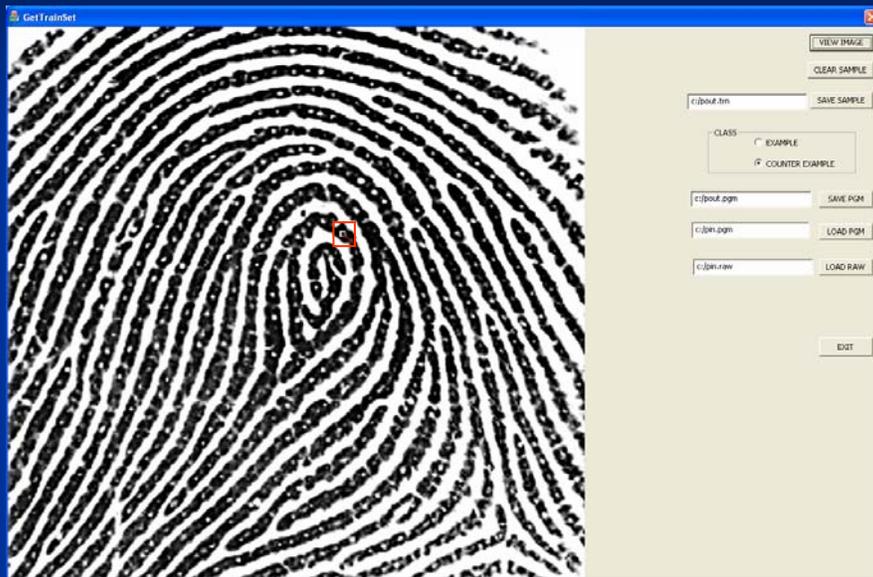
Training and Evaluation Methods

- Trained using SVM-light software
 - Courtesy of Thorsten Joachims [Joachims, 2002a] [Joachims, 2002c] [Klinkenberg, Joachims, 2000a] [Joachims, 2000b] [Joachims, 1999a]
 - Available without charge at <http://svmlight.ioachims.org>
 - Another version [CHANG 2001], LIBSVM, also available without charge
- Radial Basis Function Kernel was used
 - $K(x_i, x_j) = \exp(-\gamma || x_i^T - x_j ||^2)$
- Accuracy evaluated by leave-one-out method

Characteristics of SVMs

- Generalizes from training examples
- Constructs arbitrarily complicated, optimal, non-linear decision surfaces
- Every solution is global; no local minima
- Training is a conventional quadratic programming problem
 - Many different optimizers can be used
 - Specialized optimizers improve performance
- Training complexity is calculable
 - Cubic in number of support vectors
 - Support vectors are typically much fewer than training vectors
- Provides confidence level on decisions
- Accuracy estimate is produced with little additional computation
 - Leave-one-out cross validation

Training Set Selection Program



Training Set Example Selection

- Select correct classification
- Click on an image point
 - Computer program determines training vector components
- Save as training vector
- Components currently based on:
 - Central intensity pattern
 - Radial intensity pattern
- Ridge slope is estimated
 - Will be used for other level 3 features

Estimating Accuracy

- **Cross validation**, the basic procedure
 - Separate data set into two sub sets
 - Training set
 - Test set
 - Train classifier on Training Set
 - Measure accuracy on Test Set
- **n set Cross validation** improves accuracy
 1. Separate data into n sub-sets
 2. Train on n - 1 subsets, reserving one subset
 3. Measure accuracy on reserved sub set
 4. Repeat 2 through 3 for all sub-sets
- **Leave-One-Out method**, limit of n set method, still more accurate
 1. Train on all but 1 example
 2. Classify that example
 3. Repeat steps 1 and 2 for all examples
 4. Calculate error rate as: number of errors / number of training examples
 - Impractical for many types of classifiers: requires re-training for each example
- SVM performs Leave-One-Out accuracy estimation with n sequential computation

Training Process

- Training set size: 483 samples
- CPU time for training: < .01 seconds
- CPU time for classification: < .01 seconds
- CPU time for leave-one-out cross-validation: .03 seconds.

Estimated Accuracy by Leave-One-Out Method

- **No errors found by cross-validation**
- Recall: 100% ($\text{TAR} \times 100$)
 - Percentage of pores correctly classified (221 pores; 221 correctly classified)
- Precision: 100%
 - Percentage of samples classified as a pores that actually are pores
- Overall accuracy: 100%
 - 483 samples; 483 correctly classified, 0 misclassified
 - 262 pores; 262 correctly classified. 0 misclassified
 - 221 non-pores, all correctly classified

Estimated Accuracy

- TAR (True Accept Rate) = 1.0
- FAR (False Accept Rate) = 0.0

Discussion

- Results are suggestive, but not conclusive
- Sample size is too small to make useful accuracy estimates
 - Because there were no errors, with 95% confidence, the error rate is known to be less than 0.621% ($3/\text{sample size}$) (Rule of 3)
[Gamassi, 2004] [Louis 1981] [Jovanovic 1997] [Wayman 2000]
- Errors are too few in number
 - “To be 90% confident that the true error rate is within $\pm 30\%$ of the observed error rate, there must be at least 30 errors.”
[Gamassi, 2004] [Doddington, 2000] (Rule of 30)

Future Research

- Expand and evaluate pore training set
- Scan image for pores and display detection regions
- Calculate ROC using confidence levels
- Evaluate performance on other level 3 features
- Expand study to include 1000 dpi fingerprints
- Scan latent fingerprint images and display detection regions

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